Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | John P. Sheehan | 1742 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,478,897	11-2002	Izumida et al.	148/428
	В	US-6,475,427	11-2002	Deshmukh et al.	419/8
	С	US-6,200,688	03-2001	Liang et al.	428/544
	D	US-5,938,543	08-1999	McGeeney et al.	473/324
	Е	US-4,692,305	09-1987	Rangaswamy et al.	420/436
	F	US-2003/0000341	01-2003	Amick, Darryl D.	75/352
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	59-70744	04-1984	Japan	Yabuki et al.	420/448
	0					
	Р					
	Q					
	R					·
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Derwent Abstract 2003-842132 for Patent Document No. TW537916A June 2003			
	٧				
	w				
	Х				

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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